

**Notice of References Cited**

Application/Control No.

09/110,667

Applicant(s)/Patent Under  
Reexamination  
BOYLAN III ET AL.

Examiner

Son P Huynh

Art Unit

2611

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,734,853	03-1998	Hendricks et al.	395/352
	B	US-5,940,073	08-1999	Klosterman et al.	345/327
	C	US-6,078,348	06-2000	Klosterman et al.	348/10
	D	US-5,917,830	06-1999	Chen et al.	370/487
	E	US-6,160,545	12-2000	Eyer et al.	345/327
	F	US-6,177,931	01-2001	Alexander et al.	345/327
	G	US-5,689,648	11-1997	Diaz et al.	395/226
	H	US-6,064,376	05-2000	Berezowski et al.	345/327
	I	US-4,814,883	03-1989	Perine et al.	358/181
	J	US-5,424,770	06-1995	Schmelzer et al.	348/9
	K	US-5,907,366	05-1999	Farmer et al.	348/478
	L	US-6,173,271	01-2001	Goodman et al.	705/40
	M	US-5,929,849	07-1999	Kikinis	345/327

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 9749241	12-1997		Ban Moshe	H04N 007/10
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.